

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of: Kie Y. Ahn et al.

Title: ATOMIC LAYER-DEPOSITED LaAIO3 FILMS FOR GATE DIELETRICS

Attorney Docket No .:

1303.050US2

Customer No.: 21186

PATENT APPLICATION TRANSMITTAL

MAIL STOP PATENT APPLICATION Commissioner for Patents

P.O. Box 1450

Alexandria, VA 22313-1450

We are transmitting herewith the following attached items and information (as indicated with an "X"):

Return postcard.

- **DIVISIONAL** of prior Patent Application No. (10/137499) (under 37 CFR 1.53(b)) comprising: X
 - Specification (38 pgs, including claims numbered 1 through 45 and a 1 page Abstract).
 - Formal Drawing(s) (8 sheets).
 - Copy of signed Declaration (6 pgs) from prior application.
 - Copy of Power of Attorney from prior application (1 pgs).
 - $\frac{X}{X}$ Incorporation by Reference: The entire disclosure of the prior application, from which a copy of the oath or declaration is supplied herewith, is considered as being part of the disclosure of the accompanying application and is hereby incorporated by reference therein.
 - Check in the amount of \$1564.00 to pay the filing fee. X
- Prior application is assigned of record to Micron Technology, Inc.
- Information Disclosure Statement (1 pgs), Form 1449 (7 pgs) References NOT enclosed, cited in prior application.
- Communication Concerning Related Applications (4 pgs.).

The filing fee has been calculated below as follows:

| | No. Filed | No. Extra | Rate | Fee |
|--------------------|-----------|-----------|-----------|-----------|
| TOTAL CLAIMS | 45-20 | 25 | x 18.00 = | \$450.00 |
| INDEPENDENT CLAIMS | 7-3 | 4 | x 86.00 = | \$344.00 |
| [] MULTIPLE I | \$0.00 | | | |
| | \$770.00 | | | |
| TOTAL | | | | \$1564.00 |

Please consider this a PETITION FOR EXTENSION OF TIME for sufficient number of months to enter these papers. Please charge any additional required fees or credit overpayment to Deposit Account No. 19-0743.

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.

Customer Number: 21186

Atty: David R. Cochran

Reg. No. 46,632

"Express Mail" mailing label number: EV299683847US

Date of Deposit: February 27, 2004

This paper or fee is being deposited on the date indicated above with the United States Postal Service pursuant to 37 CFR 1.10, and is addressed to The Commissioner for Patents, Mail Stop Patent Application, P.O. Box 1450, Alexandria, VA 22313-1450.



S/N Unknown

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Kie Y. Ahn et al.

Examiner: Unknown

Serial No.:

Unknown

Group Art Unit: Unknown

Filed:

Herewith

Docket: 1303.050US2

Title:

ATOMIC LAYER-DEPOSITED LAALO3 FILMS FOR GATE DIELETRICS

COMMUNICATION CONCERNING RELATED APPLICATION(S)

MS Patent Application Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Applicants would like to bring to the Examiner's attention the following related application(s) in the above-identified patent application:

| Serial/Patent No. 09/944981 | Filing Date August 30, 2001 | Attorney Docket 1303.021US1 | Title CRYSTALLINE OR AMOPHOUS MEDIUM-K GATE OXIDES, Y203 AND Gd203 |
|-----------------------------|-----------------------------|--------------------------------|---|
| 09/945535 | August 30, 2001 | 1303.026US1 | HIGHLY RELIABLE AMORPHOUS HIGH-K GATE OXIDE ZrO2 |
| 10/028643 | December 20, 2001 | 1303.030US1 | LOW-TEMPERATURE GROWN HIGH QUALITY ULTRA-THIN CoTiO3 GATE DIELECTRICS |
| 10/052983 | January 17, 2002 | 1303.031US1 | HIGHLY RELIABLE AMORPHOUS HIGH-k GATE DIELECTRIC ZrOxNy |
| 10/027315 | December 20, 2001 | 1303.033US1 | LOW-TEMPERATURE GROWN HIGH- QUALITY ULTRA-THIN PRASEODYMIUM GATE DIELECTRICS |
| 09/797324 | March 1, 2001 | 303.717US1 | METHODS, SYSTEMS, AND APPARATUS FOR UNIFORM CHEMICAL-VAPOR DEPOSITIONS |

COMMUNICATION CONCERNING RELATED APPLICATIONS

Serial Number: Unknown

Filing Date: Herewith

Title: ATOMIC LAYER-DEPOSITED LAALO3 FILMS FOR GATE DIELETRICS

न्तु र

Page 2 Dkt: 1303.050US2

| 10/099194 | March 13, 2002 | 1303.044US1 | EVAPORATION OF Y-Si-O FILMS FOR MEDIUM-k DIELETRICS |
|-----------|--------------------|-------------|---|
| 10/081439 | February 20, 2002 | 1303.046US1 | EVAPORATED LaAIO3 FILMS FOR GATE DIELECTRICS |
| 10/137058 | May 2, 2002 | 303.802US1 | ATOMIC LAYER DEPOSITION AND CONVERSION |
| 10/137168 | May 2, 2002 | 1303.048US1 | METHODS FOR ATOMIC-LAYER DEPOSITION OF ALUMINUM OXIDES IN INTEGRATED CIRCUITS |
| 10/137499 | May 2, 2002 | 1303.050US1 | ATOMIC LAYER-DEPOSITED LaAlO3 FILMS FOR GATE DIELETRICS |
| 10/163481 | June 5, 2002 | 1303.056US1 | ATOMIC LAYER-DEPOSITED HfAIO3 FILMS FOR GATE DIELECTRICS |
| 10/163686 | June 5, 2002 | 1303.059US1 | Pr2O3-BASED La-oxide GATE DIELECTRICS |
| 10/209581 | July 30, 2002 | 1303.061US1 | ATOMIC LAYER DEPOSITED NANOLAMINATES OF HfO2/ZrO2 FILMS AS GATE DIELECTRICS |
| 10/191336 | July 8, 2002 | 1303.068US1 | MEMORY UTILIZING OXIDE- CONDUCTOR NANOLAMINATES |
| 10/219870 | August 15, 2002 | 1303.069US1 | LANTHANIDE DOPED TIOX DIELECTRIC FILMS BY PLASMA OXIDATION |
| 10/219878 | August 15, 2002 | 1303.070US1 | LANTHANIDE DOPED TiOx DIELECTRIC FILMS |
| 10/229903 | August 28, 2002 | 1303.078US1 | ATOMIC LAYER DEPOSITED HISION DIELECTRIC FILMS |
| 10/233309 | August 29, 2002 | 1303.079US1 | ATOMIC LAYER DEPOSITED LANTHANIDE DOPED TIOX DIELECTRIC FILMS |

COMMUNICATION CONCERNING RELATED APPLICATIONS

Serial Number: Unknown
Filing Date: Herewith
Title: ATOMIC LAYER-DEPOSITED LAALO3 FILMS FOR GATE DIELETRICS

Page 3 Dkt: 1303.050US2

| 10/309583 | December 4, 2002 | 1303.082US1 | ATOMIC LAYER DEPOSITED ZR-SN- TI-O FILMS USING TiI4 |
|-----------|-----------------------------|-------------|---|
| 10/309935 | December 4, 2002 | 1303.083US1 | ATOMIC LAYER DEPOSITED Zr-Sn-Ti-O FILMS |
| 10/379470 | March 4, 2003 | 1303.090US1 | ATOMIC LAYER DEPOSITED DIELECTRIC LAYERS |
| 10/403734 | March 31, 2003 | 1303.092US1 | ATOMIC LAYER DEPOSITED ZrAlxOy DIELECTRIC LAYERS |
| 10/420307 | April 22, 2003 | 1303.097US1 | ATOMIC LAYER DEPOSITED ZrTiO4 FILMS |
| 10/602323 | June 24, 2003 | 1303.101US1 | LANTHANIDE OXIDE / HAFNIUM OXIDE DIELECTRIC LAYERS |
| 10/602315 | June 24, 2003 | 1303.107US1 | LANTHANIDE OXIDE / HAFNIUM OXIDE DIELECTRICS |
| 09/779959 | February 9, 2001 | | |
| 09/838335 | April 20, 2001 | | |
| 09/881408 | June 13, 2001 | | |
| 09/908767 | July 18, | • | |
| 10/765619 | 2001 January 27, 2004 | 1303.033US2 | LOW-TEMPERATURE GROWN HIGH- QUALITY ULTRA-THIN PRASEODYMIUM GATE DIELECTRICS |
| 10/768597 | January 30, 2004 | 1303.033US3 | LOW-TEMPERATURE GROWN HIGH- QUALITY ULTRA-THIN PRASEODYMIUM GATE DIELECTRICS |

COMMUNICATION CONCERNING RELATED APPLICATIONS

Serial Number: Unknown Filing Date: Herewith

Title: ATOMIC LAYER-DEPOSITED LAALO3 FILMS FOR GATE DIELETRICS

Page 4 Dkt: 1303.050US2

Respectfully submitted,

KIE Y. AHN ET AL.

By Applicants' Representatives,

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.

P.O. Box 2938

Minneapolis, MN 55402

(612) 371-2157

Date 27 rebausky 2004

David R. Cochran

Reg. No. 46,632

"Express Mail" mailing label number: EV299683847 US

Date of Deposit: February 27, 2004

This paper or fee is being deposited on the date indicated above with the United States Postal Service pursuant to 37 CFR 1.10, and is addressed to The Commissioner for Patents, Mail Stop Patent Application, P.O.Box 1450, Alexandria, VA 22313-1450.